



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In Re Application of : Ofer Du-nour  
Serial No. : 09/762,473  
Filed : 7 February 2001  
For : Methods And Apparatus For Measuring The  
Thickness Of A Film, Particularly Of A Photoresist  
Film On A Semiconductor  
Attorney Docket No. : 24982

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Filed  
USPTO  
23/9/02

**POWER OF ATTORNEY**

Director of US Patent and Trademark Office  
Washington, D.C. 20231  
USA

Sir:

I (we) hereby appoint the following attorneys or agents, with full power of substitution, association, and revocation, to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith;

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I (we) hereby revoke all Powers of Attorney previously granted.

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Date : 13/8/02